

# IGBT Chip in NPT-technology

#### **FEATURES:**

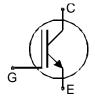
- 1200V NPT technology 175µm chip
- low turn-off losses
- short tail current
- positive temperature coefficient
- easy paralleling

# This chip is used for:

IGBT Modules

# Applications:

• drives, SMPS, resonant applications



| Chip Type     | V <sub>CE</sub> | I <sub>Cn</sub> | Die Size                    | Package      | Ordering Code         |
|---------------|-----------------|-----------------|-----------------------------|--------------|-----------------------|
| SIGC42T120CS2 | 1200V           | 25A             | 6.59 x 6.49 mm <sup>2</sup> | sawn on foil | Q67050-<br>A4338-A101 |

## **MECHANICAL PARAMETER:**

| Raster size                     | 6.59 x 6.49   | mm <sup>2</sup>                        |  |  |  |
|---------------------------------|---|--|--|--|--|
| Emitter pad size                | 2 x (2.18 x 1.58)   |  |  |  |  |
| Gate pad size                   | 1.06 x 0.65   | 7                                      |  |  |  |
| Area total / active             | 42.8 / 33.5   |  |  |  |  |
| Thickness                       | 180   | μm                                     |  |  |  |
| Wafer size                      | 150   | mm                                     |  |  |  |
| Flat position                   | 90  | grd                                    |  |  |  |
| Max.possible chips per wafer    | 334 pcs   |  |  |  |  |
| Passivation frontside           | Photoimide  | Photoimide                             |  |  |  |
| Emitter metallization           | 3200 nm Al Si 1%  |  |  |  |  |
| Collector metallization         | 1400 nm Ni Ag –system suitable for epoxy and soft solder die bo                           | onding                                 |  |  |  |
| Die bond                        | electrically conductive glue or sold  | electrically conductive glue or solder |  |  |  |
| Wire bond                       | Al, <500μm  |  |  |  |  |
| Reject Ink Dot Size             | Ø 0.65mm ; max 1.2mm  |  |  |  |  |
| Recommended Storage Environment | store in original container, in dry nitrogen, < 6 month at an ambient temperature of 23°C |  |  |  |  |



## **MAXIMUM RATINGS:**

| Parameter   | Symbol             | Value            | Unit |
|---|--------------------|------------------|------|
| Collector-emitter voltage, T <sub>j</sub> =25 °C                      | V <sub>CE</sub>    | 1200             | V    |
| DC collector current, limited by T <sub>jmax</sub>                    | I <sub>C</sub>     | 1)               | Α    |
| Pulsed collector current, t <sub>p</sub> limited by T <sub>jmax</sub> | I <sub>cpuls</sub> | 75               | А    |
| Gate emitter voltage  | V <sub>GE</sub>    | ±20              | V    |
| Operating junction and storage temperature                            | $T_j$ , $T_{stg}$  | -55 <b>+</b> 150 | °C   |

<sup>1)</sup> depending on thermal properties of assembly

# STATIC CHARACTERISTICS (tested on chip), $T_i$ =25 °C, unless otherwise specified:

| Parameter                            | Symbol Conditions    |  | Value |      |      | Unit  |
|--------------------------------------|----------------------|--|-------|------|------|-------|
| i arameter                           | Cymbol               | Conditions   | min.  | typ. | max. | J.iii |
| Collector-emitter breakdown voltage  | V <sub>(BR)CES</sub> | $V_{GE}$ =0V , $I_{C}$ = 1.5mA                         | 1200  |      |      |       |
| Collector-emitter saturation voltage | V <sub>CE(sat)</sub> | V <sub>GE</sub> =15V, I <sub>C</sub> =25A              | 2.7   | 3.2  | 3.7  | ٧     |
| Gate-emitter threshold voltage       | V <sub>GE(th)</sub>  | I <sub>C</sub> =1mA , V <sub>GE</sub> =V <sub>CE</sub> | 4.5   | 5.5  | 6.5  |       |
| Zero gate voltage collector current  | I <sub>CES</sub>     | V <sub>CE</sub> =1200V , V <sub>GE</sub> =0V           |       |      | 3    | μA    |
| Gate-emitter leakage current         | I <sub>GES</sub>     | V <sub>CE</sub> =0V , V <sub>GE</sub> =20V             |       |      | 120  | nA    |

# **ELECTRICAL CHARACTERISTICS** (tested at component):

| Parameter                    | Symbol Conditions | Value                 |      |      | Unit |       |
|------------------------------|-------------------|-----------------------|------|------|------|-------|
| raiailletei                  | Symbol            | Conditions            | min. | typ. | max. | Oilit |
| Input capacitance            | Ciss              | V <sub>CE</sub> =25V, | -    | 1.65 |      | nF    |
| Output capacitance           | Coss              | $V_{GE}=0V$ ,         | -    | 0.25 |      |       |
| Reverse transfer capacitance | Crss              | f=1MHz                | -    | 0.11 |      |       |

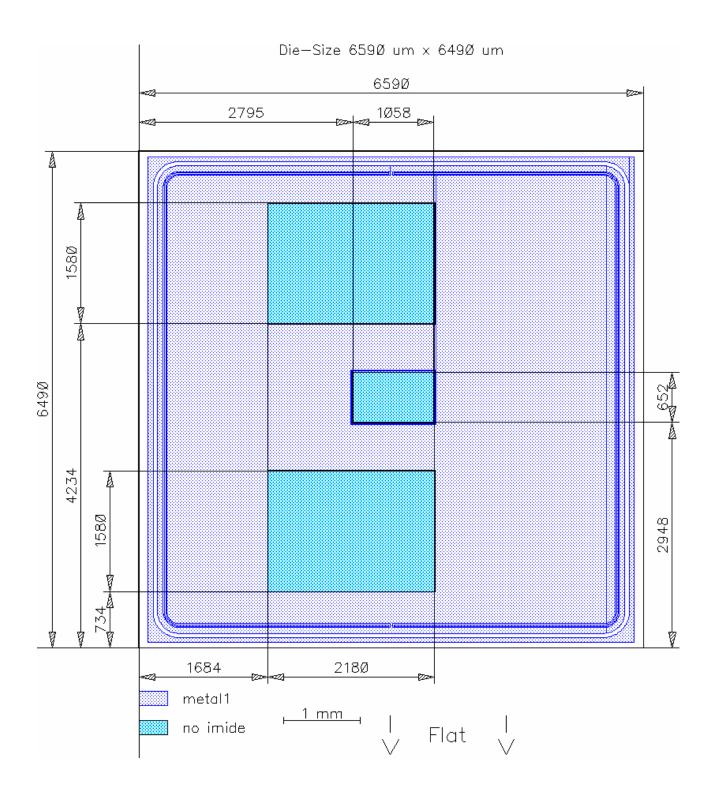
## SWITCHING CHARACTERISTICS (tested at component), Inductive Load

| Parameter           | Symbol       | Conditions 1)                                     | Value |      |      | Unit  |
|---------------------|--------------|---|-------|------|------|-------|
| raiametei           | Symbol       | Conditions  | min.  | typ. | max. | Oilit |
| Turn-on delay time  | $t_{d(on)}$  | <i>T</i> <sub>j</sub> =125°C                      | -     | 60   |      | ns    |
| Rise time           | $t_{r}$      | $V_{\rm CC} = 600  \text{V},$                     | -     | 50   |      |       |
| Turn-off delay time | $t_{d(off)}$ | I <sub>C</sub> =25A,<br>V <sub>GE</sub> =-15/15V, | -     | 400  |      |       |
| Fall time           | $t_{f}$      | $R_{\rm G}$ = 27 $\Omega$                         | -     | 60   |      |       |

<sup>&</sup>lt;sup>1)</sup> values also influenced by parasitic L- and C- in measurement and package.



### **CHIP DRAWING:**



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#### **FURTHER ELECTRICAL CHARACTERISTICS:**

| This chip data sheet refers to the device data sheet              | Eupec | FP25R12KS4C |  |  |  |  |  |
|---|-------|-------------|--|--|--|--|--|
| DESCRIPTION:  |       |             |  |  |  |  |  |
| AQL 0,65 for visual inspection according to failure catalog       |       |             |  |  |  |  |  |
| Electrostatic Discharge Sensitive Device according to MIL-STD 883 |       |             |  |  |  |  |  |
| Test-Normen Villach/Prüffeld                                      |       |             |  |  |  |  |  |

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